

| | | | | |
|-----------------------------------|---------------------------------------|--|---|-------------|
| Notice of References Cited | Application/Control No. 10/827,336 | | Applicant(s)/Patent Under Reexamination TSUCHIYA ET AL. | |
| | Examiner Ricky L Mack | | Art Unit 2873 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-5,521,036 A | 05-1996 | Iwamoto et al. | 430/22 |
| * | B | US-6,046,863 A | 04-2000 | Chino, Noriko | 359/697 |
| * | C | US-6,081,371 A | 06-2000 | Shioda et al. | 359/372 |
| * | D | US-6,661,585 B2 | 12-2003 | Okawara, Hiroto | 359/697 |
| * | E | US-6,831,793 B2 | 12-2004 | Nakamura, Hidekazu | 359/697 |
| * | F | US-2002/0171815 A1 | 11-2002 | Matsuyama et al. | 355/55 |
| * | G | US-2004/0042089 A1 | 03-2004 | Nomura, Hiroshi | 359/819 |
| * | H | US-2004/0061799 A1 | 04-2004 | Atarashi et al. | 348/340 |
| * | I | US-2004/0174614 A1 | 09-2004 | Hovanky, Thao D. | 359/694 |
| * | J | US-2004/0227845 A1 | 11-2004 | Kawai, Sumio | 348/360 |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.